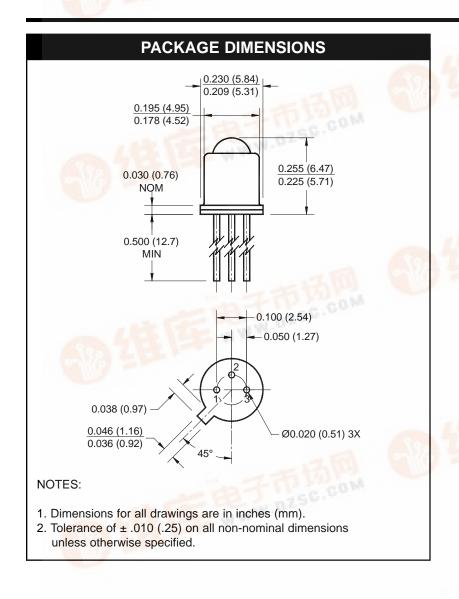
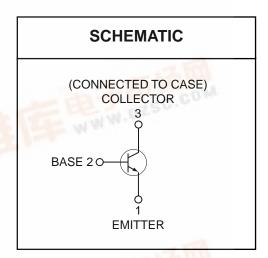


捷多邦,专业PCB打样工厂,24小时加急出货 HERMETIC SILICON PHOTOTRANSISTOR

L14P1 L14P2







DESCRIPTION

The L14P1/L14P2 are silicon phototransistors mounted in a narrow angle, TO-18 package.

FEATURES

- Hermetically sealed package
- Narrow reception angle
- Devices can be used as a photodiode by wiring the collector and base leads.





HERMETIC SILICON PHOTOTRANSISTOR

L14P1 L14P2

ABSOLUTE MAXIMUM RATINGS (T _A = 25°C unless otherwise specified)								
Parameter	Symbol	Rating	Unit					
Operating Temperature	T _{OPR}	-65 to +125	°C					
Storage Temperature	T _{STG}	-65 to +150	°C					
Soldering Temperature (Iron)(3,4,5 and 6)	T _{SOL-I}	240 for 5 sec	°C					
Soldering Temperature (Flow)(3,4 and 6)	T _{SOL-F}	260 for 10 sec	°C					
Collector to Emitter Breakdown Voltage	V _{CEO}	30	V					
Collector to Base Breakdown Voltage	V _{CBO}	40	V					
Emitter to Base Breakdwon Voltage	V _{EBO}	5	V					
Power Dissipation (T _A = 25°C) ⁽¹⁾	P _D	300	mW					
Power Dissipation (T _C = 25°C) ⁽²⁾	P _D	600	mW					

NOTE:

- 1. Derate power dissipation linearly 3.00 mW/°C above 25°C ambient.
- 2. Derate power dissipation linearly 6.00 mW/°C above 25°C case.
- 3. RMA flux is recommended.
- 4. Methanol or isopropyl alcohols are recommended as cleaning agents.
- 5. Soldering iron tip 1/16" (1.6mm) minimum from housing.
- 6. As long as leads are not under any stress or spring tension.
- 7. Light source is a GaAs LED emitting light at a peak wavelength of 940 nm.
- 8. Figure 1 and figure 2 use light source of tungsten lamp at 2870°K color temperature. A GaAs source of 3.0 mW/cm² is approximately equivalent to a tungsten source, at 2870°K, of 10 mW/cm².

ELECTRICAL / OPTICAL CHARACTERISTICS (TA =25°C) (All measurements made under pulse conditions)								
PARAMETER	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNITS		
Collector-Emitter Breakdown	$I_{\rm C} = 10 \text{ mA}, Ee = 0$	BV _{CEO}	30		_	V		
Emitter-Base Breakdown	I _E = 100 μA, Ee = 0	BV _{EBO}	5.0		_	V		
Collector-Base Breakdown	I _C = 100 μA, Ee = 0	BV _{CBO}	40		_	V		
Collector-Emitter Leakage	V _{CE} = 12 V, Ee = 0	I _{CEO}	_		100	nA		
Reception Angle at 1/2 Sensitivity		θ		±8		Degrees		
On-State Collector Current L14P1	Ee = 0.5 mW/cm ² , $V_{CE} = 5 V^{(7,8)}$	I _{C(ON)}	6.5		_	mA		
On-State Collector Current L14P2	Ee = 0.5 mW/cm ² , $V_{CE} = 5 V^{(7,8)}$	I _{C(ON)}	13.0			mA		
On-State Photodiode Current	Ee = 0.3 mW/cm ² , $V_{CB} = 5 V$	I _{CB(ON)}		6.0		μΑ		
Rise Time	$I_{C} = 10 \text{ mA}, V_{CC} = 5 \text{ V}, R_{L} = 100 \Omega$	t _r		10		μs		
Fall Time	$I_C = 10 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 100 \Omega$	t _f		12		μs		
Saturation Voltage L14P1	$I_C = 0.8 \text{ mA}, Ee = 0.6 \text{ mW/cm}^{2(7,8)}$	V _{CE(SAT)}			0.40	V		
Saturation Voltage L14P2	$I_C = 1.6 \text{ mA}, Ee = 0.6 \text{ mW/cm}^{2(7,8)}$	V _{CE(SAT)}	_		0.40	V		



.02

HERMETIC SILICON PHOTOTRANSISTOR

L14P1 L14P2

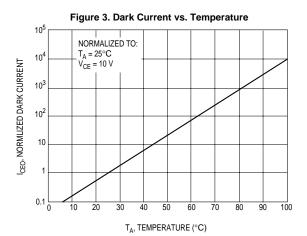
Figure 1. Light Current vs. Collector to Emitter Voltage NORMALIZED TO: -Ee = 20 mW/cm2 Ee = 10 mW/cm² $E_e = 1 \text{ mW/cm}^2$ $V_{CE} = 5 \text{ V}$ $T_{\Delta} = 25^{\circ}\text{C}$ I_L, NORMALIZED LIGHT CURRENT PÜLSED Ee = 1 mW/cm² t_p = 300 μsec $Ee = 5 \text{ mW/cm}^2$ Ee = 0.5 mW/cm $Ee = 0.2 \text{ mW/cm}^2$ Ee = 0.1 mW/cm .06 .04 .02 .01

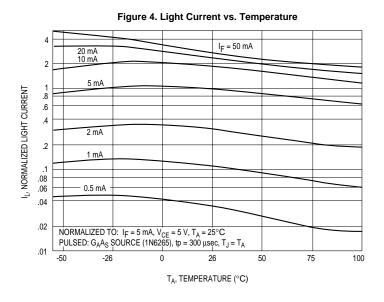
.4 .6 .8 1

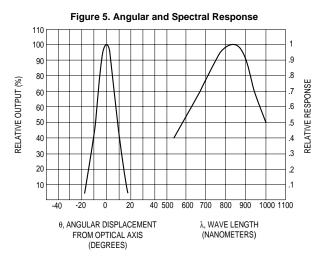
 V_{CE} , COLLECTOR TO EMITTER VOLTAGE (V)

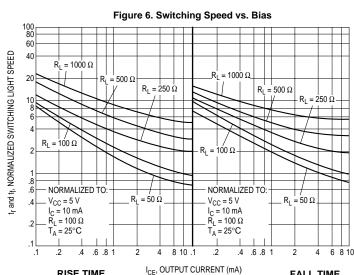
6 8 10

Figure 2. Light Current vs. Temperature 2 I, NORMALIZED LIGHT CURRENT .8 .6 .2 NORMALIZED TO: $V_{CE} = 5 \text{ V}$ $E_e = 1 \text{ mW/cm}^2$ $T_A = 25^{\circ}\text{C}$.08 .04 PULSED t_D = 300 μsec .02 .01 ^L .6 6 8 10 20 E_e - TOTAL IRRADIANCE IN mW/cm²











HERMETIC SILICON PHOTOTRANSISTOR

L14P1 L14P2

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